

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/734,348 | | Applicant(s)/Patent Under Reexamination BANATWALA ET AL. | |
| | Examiner Backhean Tiv | | Art Unit 2151 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-5,247,615 | 09-1993 | Mori et al. | 709/205 |
| | B | US-2001/0025299 | 09-2001 | Chang et al. | 709/204 |
| | C | US-2002/0095355 | 07-2002 | Walker et al. | 705/26 |
| | D | US-2004/0003044 | 01-2004 | Teoh et al. | 709/205 |
| | E | US-2005/0033622 | 02-2005 | Kuo et al. | 705/008 |
| | F | US-2004/0103118 | 05-2004 | Irving et al. | 707/104.1 |
| | G | US-2001/0029501 | 10-2001 | Yokobori et al. | 707/10 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.